

## Matched N-Channel JFET Pairs

## Product Summary

Part Number	$V_{GS(off)}$ (V)	$V_{(BR)GSS}$ Min (V)	$g_{fs}$ Min (mS)	$I_G$ Typ (pA)	$ V_{GS1} - V_{GS2} $ Max (mV)
2N5564	-0.5 to -3	-40	7.5	-3	5
2N5565	-0.5 to -3	-40	7.5	-3	10
2N5566	-0.5 to -3	-40	7.5	-3	20

## Features

- Two-Chip Design
- High Slew Rate
- Low Offset/Drift Voltage
- Low Gate Leakage: 3 pA
- Low Noise: 12 nV/ $\sqrt{\text{Hz}}$  @ 10 Hz
- Good CMRR: 76 dB
- Minimum Parasitics

## Benefits

- Tight Differential Match vs. Current
- Improved Op Amp Speed, Settling Time Accuracy
- Minimum Input Error/Trimming Requirement
- Insignificant Signal Loss/Error Voltage
- High System Sensitivity
- Minimum Error with Large Input Signals
- Maximum High Frequency Performance

## Applications

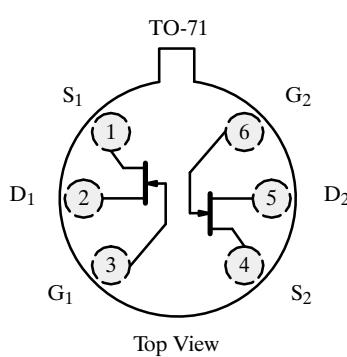
- Wideband Differential Amps
- High-Speed, Temp-Compensated, Single-Ended Input Amps
- High-Speed Comparators
- Impedance Converters
- Matched Switches

## Description

The 2N5564/5565/5566 are matched pairs of JFETs mounted in a TO-71 package. This two-chip design reduces parasitics for good performance at high frequency while ensuring extremely tight matching. This series features high breakdown voltage ( $V_{(BR)DSS}$  typically > 55 V), high gain (typically > 9 mS), and <5-mV offset between the two die.

The hermetically-sealed TO-71 package is available with full military processing (see Military Information).

For similar products see the low-noise U/SST401 series, and the low-leakage 2N5196/5197/5198/5199 data sheets.



Top View

## Absolute Maximum Ratings

Gate-Drain, Gate-Source Voltage .....	-40 V
Gate-Gate Voltage .....	$\pm 80$ V
Gate Current .....	50 mA
Lead Temperature (1/16" from case for 10 sec.) .....	300 °C
Storage Temperature .....	-65 to 200°C

Operating Junction Temperature ..... -55 to 150°C

Power Dissipation : Per Side<sup>a</sup> ..... 325 mW  
Total<sup>b</sup> ..... 650 mW

## Notes

- a. Derate 2.6 mW/°C above 25°C  
b. Derate 5.2 mW/°C above 25°C

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2N5564/5565/5566

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**Specifications<sup>a</sup>**

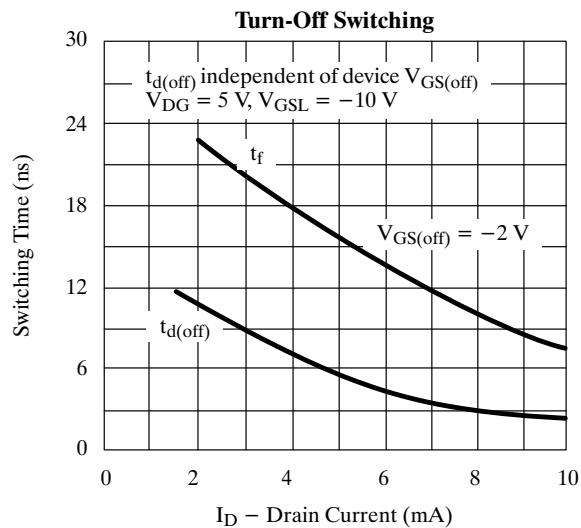
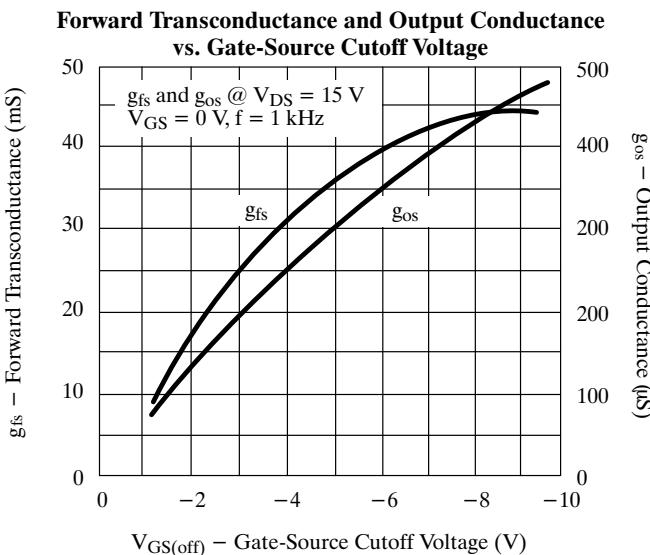
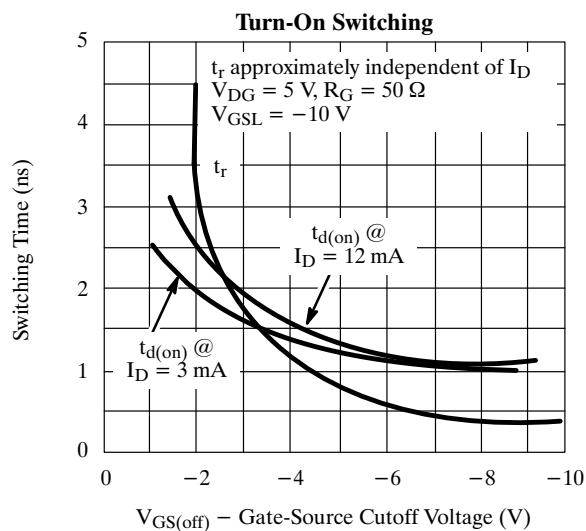
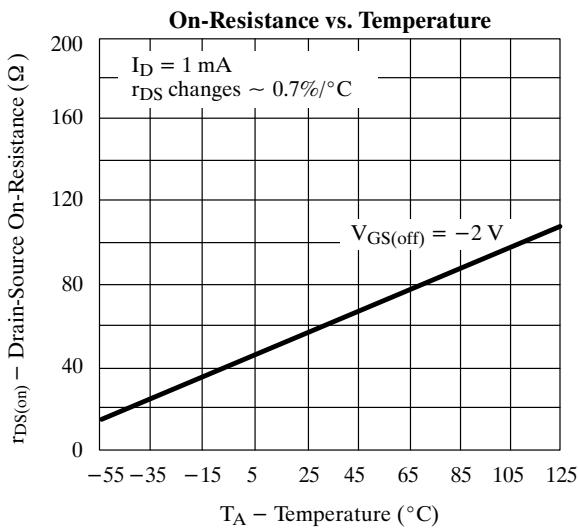
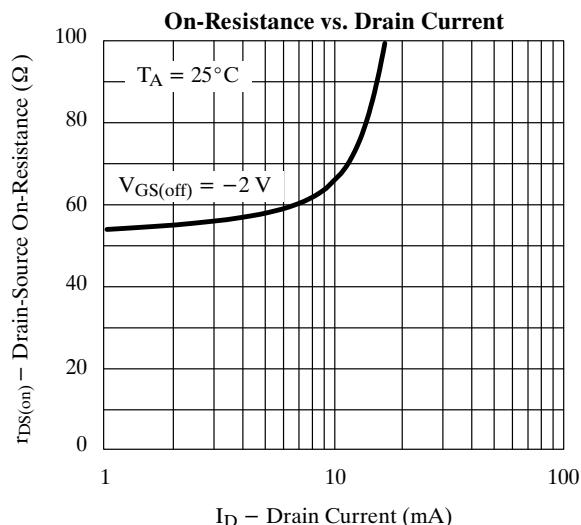
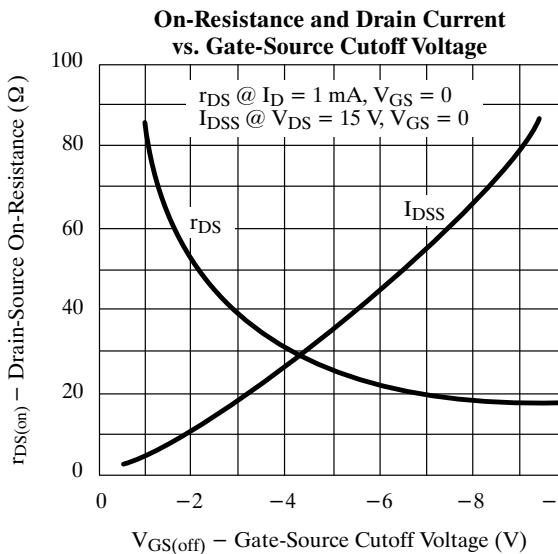
Parameter	Symbol	Test Conditions	Typ <sup>b</sup>	Limits						Unit	
				2N5564		2N5565		2N5566			
				Min	Max	Min	Max	Min	Max		
<b>Static</b>											
Gate-Source Breakdown Voltage	V <sub>(BR)GSS</sub>	I <sub>G</sub> = -1 μA, V <sub>DS</sub> = 0 V	-55	-40		-40		-40		V	
Gate-Source Cutoff Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 1 nA	-2	-0.5	-3	-0.5	-3	-0.5	-3		
Saturation Drain Current <sup>c</sup>	I <sub>DSS</sub>	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V	20	5	30	5	30	5	30	mA	
Gate Reverse Current	I <sub>GSS</sub>	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V T <sub>A</sub> = 150°C	-5 -10		-100 -200		-100 -200		-100 -200	pA nA	
Gate Operating Current <sup>d</sup>	I <sub>G</sub>	V <sub>DG</sub> = 15 V, I <sub>D</sub> = 2 mA T <sub>A</sub> = 125°C	-3 -1							pA nA	
Drain-Source On-Resistance	r <sub>DS(on)</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA	50		100		100		100	Ω	
Gate-Source Voltage <sup>d</sup>	V <sub>GS</sub>	V <sub>DG</sub> = 15 V, I <sub>D</sub> = 2 mA	-1.2							V	
Gate-Source Forward Voltage	V <sub>GS(F)</sub>	I <sub>G</sub> = 2 mA, V <sub>DS</sub> = 0 V	0.7		1		1		1		
<b>Dynamic</b>											
Common-Source Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2 mA f = 1 kHz	9	7.5	12.5	7.5	12.5	7.5	12.5	mS	
Common-Source Output Conductance	g <sub>os</sub>		35		45		45		45	μS	
Common-Source Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2 mA f = 100 MHz	8.5	7		7		7		mS	
Common-Source Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2 mA f = 1 MHz	10		12		12		12	pF	
Common-Source Reverse Transfer Capacitance	C <sub>rss</sub>		2.5		3		3		3		
Equivalent Input Noise Voltage	ē <sub>n</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2 mA f = 10 Hz R <sub>G</sub> = 10 MΩ	12		50		50		50	nV/√Hz	
Noise Figure	NF				1		1		1	dB	
<b>Matching</b>											
Differential Gate-Source Voltage	V <sub>GS1</sub> -V <sub>GS2</sub>	V <sub>DG</sub> = 15 V, I <sub>D</sub> = 2 mA			5		10		20	mV	
Gate-Source Voltage Differential Change with Temperature	Δ V <sub>GS1</sub> -V <sub>GS2</sub>   / ΔT	V <sub>DG</sub> = 15 V, I <sub>D</sub> = 2 mA T <sub>A</sub> = -55 to 125°C			10		25		50	μV/°C	
Saturation Drain Current Ratio <sup>d</sup>	I <sub>DSS1</sub> / I <sub>DSS2</sub>	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V	0.98	0.95	1	0.95	1	0.95	1		
Transconductance Ratio	g <sub>fs1</sub> / g <sub>fs2</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2 mA f = 1 kHz	0.98	0.95	1	0.90	1	0.90	1		
Common Mode Rejection Ratio <sup>d</sup>	CMRR	V <sub>DG</sub> = 10 to 20 V I <sub>D</sub> = 2 mA	76							dB	

## Notes

- a. T<sub>A</sub> = 25°C unless otherwise noted.  
b. Typical values are for DESIGN AID ONLY, not guaranteed nor subject to production testing.  
c. Pulse test: PW ≤ 300 μs duty cycle ≤ 3%.  
d. This parameter not registered with JEDEC.

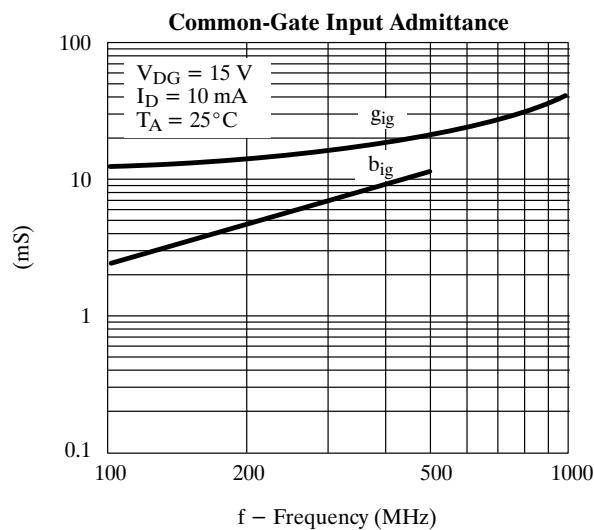
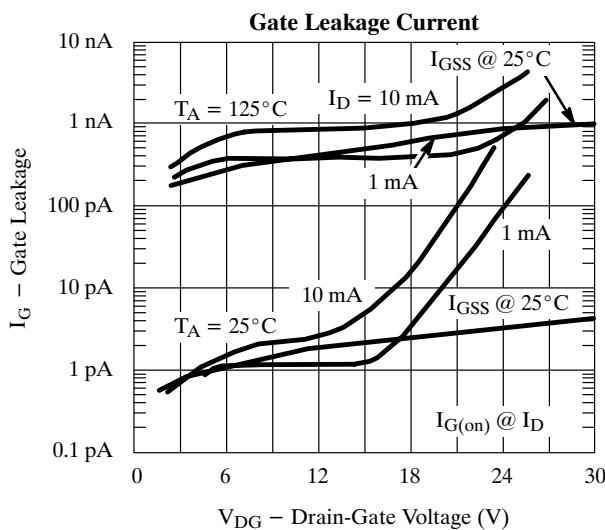
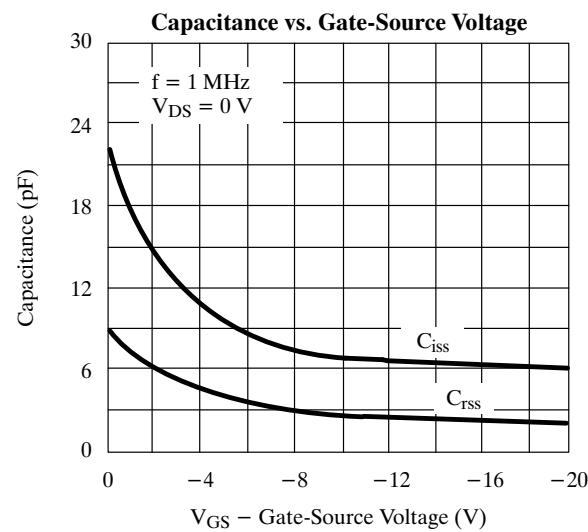
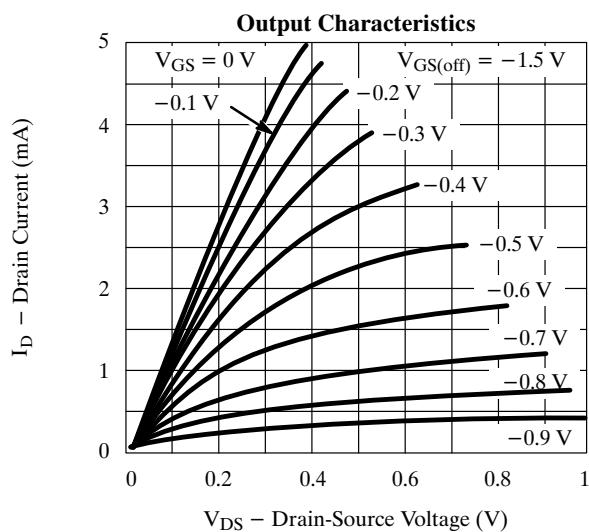
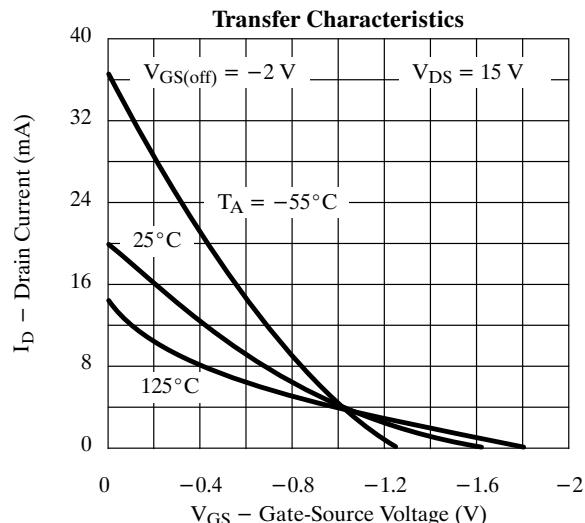
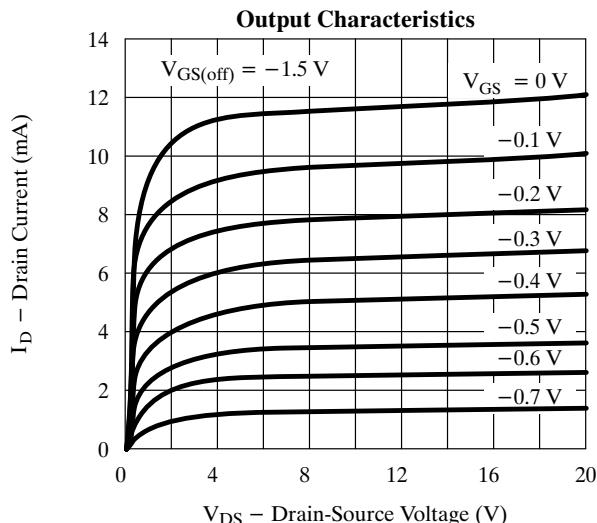
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## Typical Characteristics



# 2N5564/5565/5566

## Typical Characteristics (Cont'd)



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## Typical Characteristics (Cont'd)

